Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/679,290	SHISHIDO, CHLE		
Examiner	Art Unit		
Alex Liew	2624	•	

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Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
382/141-152,154 limited to text search	3/7/2007	AL
382/141-152,154 limited to text search	9/13/2007	AL